PH3120L

N-channel TrenchMOS logic level FET

Rev. 03 — 30 March 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Higher operating power due to low thermal resistance
- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources

1.3 Applications

- DC-to-DC convertors
- Notebook computers

- Portable equipment
- Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11	-	12.8	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{see } \frac{\text{Figure 10}}{\text{otherwise}}}$	-	2.25	2.65	mΩ



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Pinning information

Pinning information Table 2.

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		$G \stackrel{\longleftarrow}{\Longrightarrow} \stackrel{\longleftarrow}{A}$
4	G	gate	q	<u> </u>
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

Ordering information 3.

Table 3. **Ordering information**

Type number	Package		
	Name	Description	Version
PH3120L	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

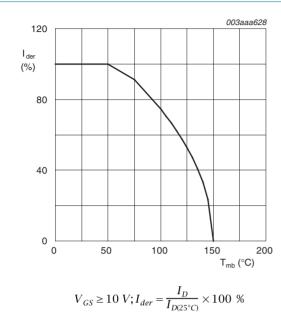
Limiting values

Limiting values Table 4.

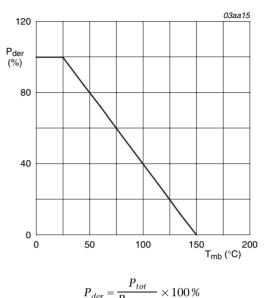
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	20	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	100	Α
		V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	76	Α
I _{DM}	peak drain current	$t_p \le 10 \mu s$; pulsed; $T_{mb} = 25 ^{\circ}C$; see Figure 3	-	300	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}C$	-	52	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	152	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C; } I_D = 46.2 \text{ A; } V_{sup} \leq 20 \text{ V;}$ unclamped; $t_p = 0.32 \text{ ms; } R_{GS} = 50 \Omega$	-	210	mJ

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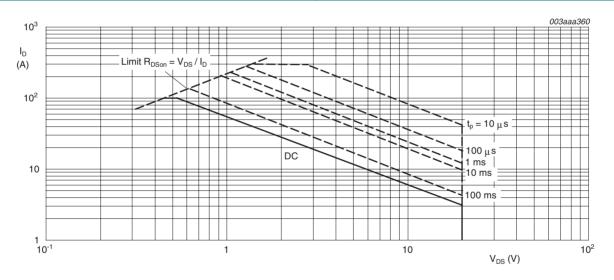


Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse; $V_{GS} = 10V$

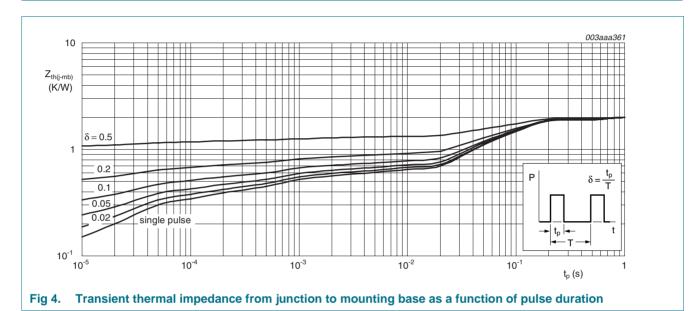
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 10 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	20	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	0.65	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.5	2	V
I _{DSS}	drain leakage current	$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	500	μΑ
		$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.06	1	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	2.25	2 500 3 1 100 100 5 2.65 6.3 3.7	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 150 °C;$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	5.1		mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9; see Figure 10	-	3		mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 50 \text{ A}; V_{DS} = 10 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	48.5	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	12.7	-	nC
Q_{GD}	gate-drain charge		-	12.8	-	nC
C _{iss}	input capacitance	$V_{DS} = 10 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	4457	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	1480	-	pF
C _{rss}	reverse transfer capacitance		-	940	-	pF
d(on)	turn-on delay time	$V_{DS} = 10 \text{ V}; R_L = 0.4 \Omega; V_{GS} = 4.5 \text{ V};$	-	34	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$; $T_j = 25 °C$; $I_D = 25 A$	-	90	-	ns
t _{d(off)}	turn-off delay time		-	114	-	ns
t _f	fall time		-	88	-	ns
Source-di	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 13	-	0.77	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$; $V_{DS} = 20 \text{ V}$; $T_i = 25 \text{ °C}$	-	63	-	ns

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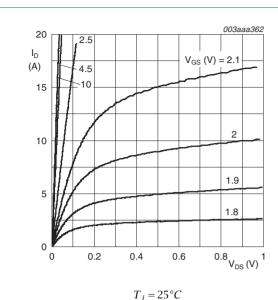
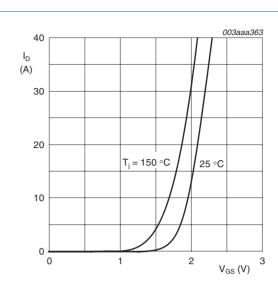
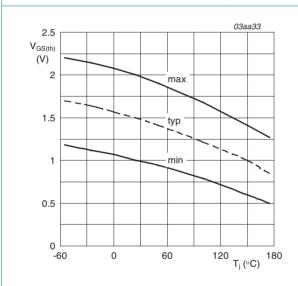


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



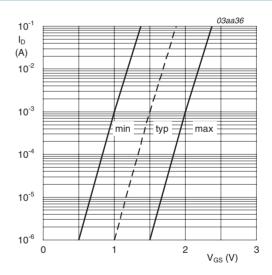
$$T_j = 25$$
° C and 150 ° C ; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 7. Gate-source threshold voltage as a function of junction temperature



 $T_i = 25 \,^{\circ}C; V_{DS} = V_{GS}$

Fig 8. Sub-threshold drain current as a function of gate-source voltage

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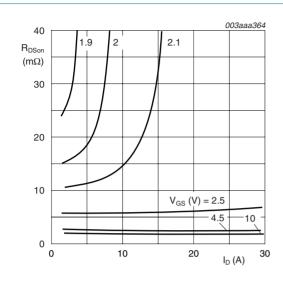


Fig 9. Drain-source on-state resistance as a function of drain current; typical values

 $T_i = 25^{\circ}C$

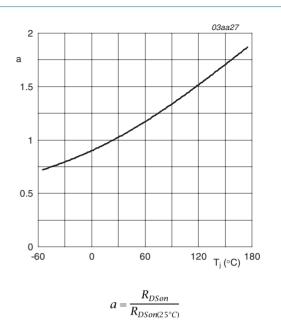


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature

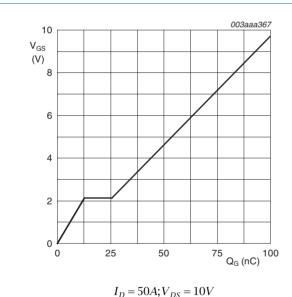
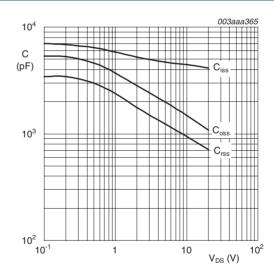


Fig 11. Gate-source voltage as a function of gate charge; typical values



 $V_{\it GS} = 0V; f = 1MHz$ 12. Input, output and reverse transfer of

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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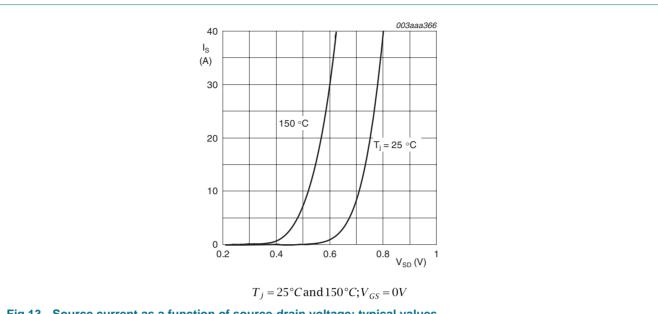
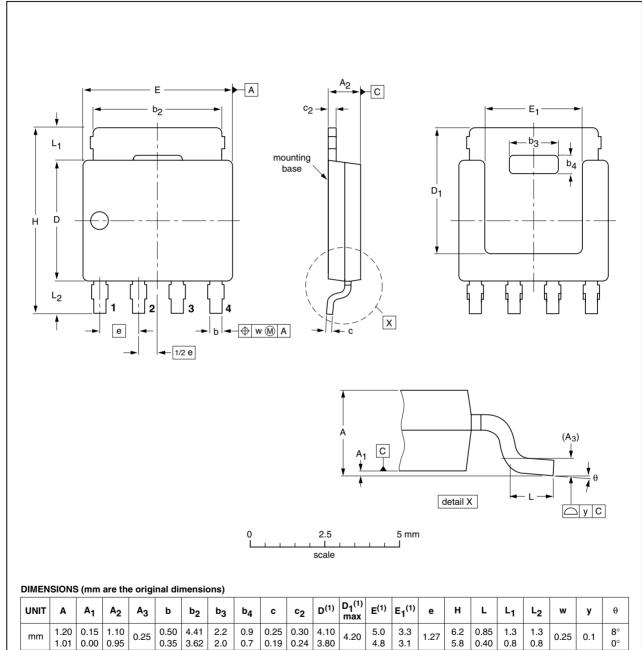


Fig 13. Source current as a function of source-drain voltage; typical values

7. Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION			REFER	ENCES	EUROPEAN	ISSUE DATE
		IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
	SOT669		MO-235			04-10-13 06-03-16

Fig 14. Package outline SOT669 (LFPAK)

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Revision history

Table 7. **Revision history**

Product data sheet

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH3120L_3	20090330	Product data sheet	-	PH3120L_2
Modifications:	guideline	at of this data sheet has been sof NXP Semiconductors.	· ·	
	 Legal tex 	ts have been adapted to the	e new company name	where appropriate.
PH3120L_2 (9397 750 14089)	20050120	Product data sheet	-	PH3120L-01
PH3120L-01 (9397 750 12812)	20040304	Preliminary data sheet	-	-

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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